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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/647,985 Confirmation No. 3087
Applicant: Patricia Beauregard Smith, et al.
Filed: August 26, 2003
Art Unit: 1746
Examiner: Zeinab El-Arini

Docket No. : TI-33260
Customer No. : 23494

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97 & 1.98

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(a)
I hereby certify that the above correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 1-19-06.

Ann Trent
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Dear Sir:

Applicants wish to bring to the attention of the Patent and Trademark Office the information noted on the enclosed PTO/SB/08A.

In accordance with 37 CFR 1.97 (d), this Information Disclosure Statement is being submitted before payment of the issue fee and is accompanied by the following certification specified in 37 CFR 1.97 (e).

On information and belief, I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Pursuant to 37 CFR 1.97 (d), Applicants respectfully petition that this Information Disclosure Statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Texas Instruments Incorporated, Account No. 20-0668, and please credit any excess fees to such Deposit Account.

Respectfully submitted,

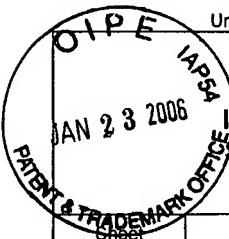


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| Application Number | 10/647,985 |
| Filing Date | August 26, 2003 |
| First Named Inventor | Patricia Beauregard Smith, et al. |
| Group Art Unit | 1746 |
| Examiner Name | Zeinab El-Arini |
| Attorney Docket No. | TI-33260 |

U.S. PATENT DOCUMENTS

| Exam. Initials* | Cite No. ¹ | U.S. Patent Document | | Name of Patentee or Applicant of Cited Doc. | Date of Pub. of Cited Doc. (mm-dd-yyyy) | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
|-----------------|-----------------------|----------------------|-----------------------------------|---------------------------------------------|-----------------------------------------|---------------------------------------------------------------------------|
| | | Number | Kind Code ² (if known) | | | |
| AA | 2003/0104320 | A1 | | Nguyen et al. | 08/05/2003 | |
| AB | 2003/0008518 | A1 | | Chang et al. | 01/09/2003 | |
| AC | 6,107,202 | | | Chiu et al. | 08/22/2000 | |
| AD | 6,100,183 | | | Lu et al. | 08/08/2000 | |
| AE | 5,798,323 | | | Honda et al. | 08/25/1998 | |
| AF | 5,643,407 | | | Chang | 07/01/1997 | |
| AG | | | | | | |
| AH | | | | | | |
| AI | | | | | | |
| AJ | | | | | | |

FOREIGN PATENT DOCUMENTS

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NON PATENT LITERATURE DOCUMENTS

| Exam. Initials* | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T ² |
|-----------------|-----------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|----------------|
| CA | | OKUDA, Seiichiro, et al., "New Dry Tool after Cleaning of Low-k Dielectrics," <i>Solid State Phenomena</i> , Vol. 92, 2003, pp. 287-291, Proceedings of Ultra Clean Processing of Silicon Surfaces Conference, April 15, 2003, Diffusion and Defect Data, Solid State Data, Part B, Vaduz, LI, September 2003. | |
| CB | | YANG, S.C., et al., "Process Optimization of Hydrogen Silsesquioxane (HSQ) Via Etch for 0.18um Technology and Beyond," Advanced Metallization Conference 1999, Orlando, Florida, September 28-30, 1999, pp. 455-459. | |
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¹Unique citation designation number. ²Applicant is to place a check mark here if English Translation is attached.